Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/620,126	KRUCK, STEFAN	
Examiner	Art Unit	

3679

Aaron M. Dunwoody

SEARCHED					
Class	Subclass	Date	Examiner		
285	401,327	5/29/2006	AMD		
	:				

INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
	-		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		